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# 3.0-V TO 5.5-V, 12-BIT, 200-KSPS, 4-/8-CHANNEL, LOW-POWER SERIAL ANALOG-TO-DIGITAL CONVERTER WITH AUTOPOWER-DOWN

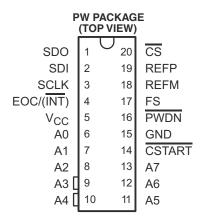
Check for Samples: TLV2548-EP

#### **FEATURES**

- Maximum Throughput 200-KSPS
- Built-In Reference, Conversion Clock and 8x FIFO
- Differential/Integral Nonlinearity Error: ±1.2 LSB
- Signal-to-Noise and Distortion Ratio: 70 dB, f<sub>i</sub> = 12 kHz
- Spurious Free Dynamic Range: 75 dB, f<sub>i</sub> = 12 kHz
- SPI (CPOL = 0, CPHA = 0)/DSP-Compatible Serial Interfaces With SCLK up to 20 MHz
- Single Wide Range Supply 3.0 Vdc to 5.5 Vdc
- Analog Input Range 0 V to Supply Voltage With 500-kHz BW
- Hardware Controlled and Programmable Sampling Period
- Low Operating Current (1.0 mA at 3.3 V, 2.0 mA at 5.5 V With External Ref, 1.7-mA at 3.3V, 2.4-mA at 5.5-V With Internal Ref)
- Power Down: Software/Hardware Power-Down Mode (1 µA Max, Ext Ref), Autopower-Down Mode (1 µA, Ext Ref)
- Programmable Auto-Channel Sweep

# SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

- Controlled Baseline
- One Assembly/Test Site
- One Fabrication Site
- Available in Military (–55°C/125°C)
   Temperature Range<sup>(1)</sup>
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability



(1) Custom temperature ranges available

#### DESCRIPTION

The TLV2548 is a high performance, 12-bit low-power, 3.86-µs, CMOS analog-to-digital converter (ADC) which operates from a single 3.0-V to 5.5-V power supply. This device has three digital inputs and a 3-state output [chip select (CS), serial input-output clock (SCLK), serial data input (SDI), and serial data output (SDO)] that provide a direct 4-wire interface to the serial port of most popular host microprocessors (SPI interface). When interfaced with a TI DSP, a frame sync (FS) signal is used to indicate the start of a serial data frame.

In addition to a high-speed A/D converter and versatile control capability, this device has an on-chip analog multiplexer that can select any analog inputs or one of three internal self-test voltages. The sample-and-hold function is automatically started after the fourth SCLK edge (normal sampling) or can be controlled by a special pin, CSTART, to extend the sampling period (extended sampling). The normal sampling period can also be programmed as short (12 SCLKs) or as long (24 SCLKs) to accommodate faster SCLK operation popular among high-performance signal processors. The TLV2548 is designed to operate with very low power consumption. The power-saving feature is further enhanced with software/hardware/autopower-down modes and programmable conversion speeds. The conversion clock (OSC) and reference are built-in. The converter can use the external SCLK as the source of the conversion clock to achieve higher (up to 2.8 µs when a 20-MHz SCLK is used) conversion speed. Two different internal reference voltages are available. An optional external reference can also be used to achieve maximum flexibility.

The TLV2548 is characterized for operation from -55°C to 125°C.



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#### **FUNCTIONAL BLOCK DIAGRAM**

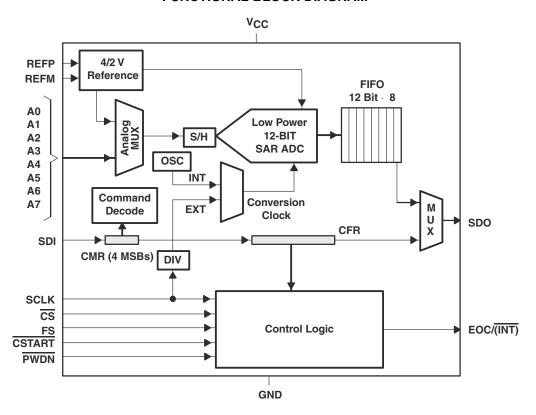


Table 1. ORDERING INFORMATION<sup>(1)</sup>

T <sub>A</sub>	PACI	KAGE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING
–55°C to 125°C	TSSOP-PW	Tape and Reel of 2000	TLV2548MPWREP	TV2548EP

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI Web site at www.ti.com.

#### **Table 2. TERMINAL FUNCTIONS**

TER	TERMINAL		DECORPORTOR	
NAME	NO.	I/O	DESCRIPTION	
A0 A1 A2 A3 A4 A5 A6 A7	6 7 8 9 10 11 12	I	Analog signal inputs. The analog inputs are applied to these terminals and are internally multiplexed. The driving source impedance should be less than or equal to 1 k $\Omega$ .  For a source impedance greater than 1 k $\Omega$ , use the asynchronous conversion start signal $\overline{\text{CSTART}}$ (CSTART low time controls the sampling period) or program long sampling period to increase the sampling time.	
<del>cs</del>	20	ı	Chip select. A high-to-low transition on the $\overline{\text{CS}}$ input resets the internal 4-bit counter, enables SDI, and removes SDO from 3-state within a maximum setup time. SDI is disable within a setup time after the 4-bit counter counts to 16 (clock edges) or a low-to-high transition of $\overline{\text{CS}}$ whichever happens first.  NOTE: $\overline{\text{CS}}$ falling and rising edges need to happen when SCLK is low for a microprocess interface such as SPI.	

<sup>(2)</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

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## Table 2. TERMINAL FUNCTIONS (continued)

TERMINAL		Table 2. TERMINAL FOROTIONS (GORISHGU)		
NAME	NO.	I/O	DESCRIPTION	
CSTART	14	I	This terminal controls the start of sampling of the analog input from a selected multiplex channel. Sampling time starts with the falling edge of $\overline{CSTART}$ and ends with the rising of $\overline{CSTART}$ as long as $\overline{CS}$ is held high. In mode 01, select cycle, $\overline{CSTART}$ can be issue soon as CHANNEL is selected which means the fifth SCLK during the select cycle, but effective sampling time is not started until $\overline{CS}$ goes to high. The rising edge of $\overline{CSTART}$ (when $\overline{CS}=1$ ) also starts the conversion. Tie this terminal to $V_{CC}$ if not used.	
EOC/(INT)	4	0	End of conversion or interrupt to host processor. [PROGRAMMED AS EOC]: This output goes from a high-to-low logic level at the end of the sampling period and remains low un the conversion is complete and data are ready for transfer. EOC is used in conversion m 00 only.  [PROGRAMMED AS INT]: This pin can also be programmed as an interrupt output signathe host processor. The falling edge of INT indicates data are ready for output. The follow CS↓ or FS clears INT.	
FS	17	I	DSP frame sync input. Indication of the start of a serial data frame in or out of the device. If FS remains low after the falling edge of $\overline{CS}$ , SDI is not enabled until an active FS is presented. A high-to-low transition on the FS input resets the internal 4-bit counter and enables SDI within a maximum setup time. SDI is disabled within a setup time after the 4-bit counter counts to 16 (clock edges) or a low-to-high transition of $\overline{CS}$ whichever happens first. Tie this terminal to $V_{CC}$ if not used. See the Data Code Information section, item 1.	
GND	15	ı	Ground return for the internal circuitry. Unless otherwise noted, all voltage measurements	
		-	are with respect to GND.  Both analog and reference circuits are powered down when this pin is at logic zero. The	
PWDN	16	I	device can be restarted by active CS, FS or CSTART after this pin is pulled back to logic one.	
SCLK	3	I	Input serial clock. This terminal receives the serial SCLK from the host processor. SCLK is used to clock the input SDI to the input register. When programmed, it may also be used a the source of the conversion clock.  NOTE: This device supports CPOL (clock polarity) = 0, which is SCLK returns to zero whe idling for SPI compatible interface.	
SDI	Serial data input. The input data is presented with the MSB (D15) first. The first 4-bit D(15–12) are decoded as one of the 16 commands. The configure write commands an additional 12 bits of data.  When FS is not used (FS =1), the first MSB (D15) is expected after the falling edge of and is latched in on the rising edges of SCLK (after CS).  When FS is used (typical with an active FS from a DSP) the first MSB (D15) is expectation and is latched in on the falling edges of SCLK.		When FS is not used (FS =1), the first MSB (D15) is expected after the falling edge of $\overline{CS}$ and is latched in on the rising edges of SCLK (after $\overline{CS}$ ↓).  When FS is used (typical with an active FS from a DSP) the first MSB (D15) is expected after the falling edge of FS and is latched in on the falling edges of SCLK.  SDI is disabled within a <u>set</u> up time after the 4-bit counter counts to 16 (clock edges) or a	
SDO	1	0	The 3-state serial output for the A/D conversion result. SDO is kept in the high-impeda state when $\overline{CS}$ is high and after the $\overline{CS}$ falling edge and until the MSB is presented. Th output format is MSB first.  When FS is not used (FS = 1 at the falling edge of $\overline{CS}$ ), the MSB is presented to the S pin after the $\overline{CS}$ falling edge, and successive data are available at the rising edge of St and changed on the falling edge.  When FS is used (FS = 0 at the falling edge of $\overline{CS}$ ), the MSB is presented to SDO after falling edge of $\overline{CS}$ and FS = 0 is detected. Successive data are available at the falling of SCLK and changed on the rising edge. (This is typically used with an active FS from DSP.)  For conversion and FIFO read cycles, the first 12 bits are result from previous convers (data) followed by 4 don't care bits. The first four bits from SDO for CFR read cycles she ignored. The register content is in the last 12 bits. SDO is 3-state (float) after the 16 See the Data Code Information section, item 2.	
REFM	18	ı	External reference input or internal reference decoupling. Tie this pin to analog ground if internal reference is used.	

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TERMINAL		1/0	DESCRIPTION	
NAME	NO.	I/O	DESCRIPTION	
REFP	19	I	External reference input or internal reference decoupling (shunt capacitors of 10 µF and 0.1 µF between REFP and REFM). The maximum input voltage range is determined by the difference between the voltage applied to this terminal and the REFM terminal when an external reference is used.	
VCC	5	I	Positive supply voltage	

#### **Detailed Description**

#### **Analog Inputs and Internal Test Voltages**

The 4/8 analog inputs and three internal test inputs are selected by the analog multiplexer depending on the command entered. The input multiplexer is a break-before-make type to reduce input-to-input noise injection resulting from channel switching.

#### Converter

The TLV2548 uses a 12-bit successive approximation ADC utilizing a charge redistribution DAC. Figure 1 shows a simplified version of the ADC.

The sampling capacitor acquires the signal on Ain during the sampling period. When the conversion process starts, the SAR control logic and charge redistribution DAC are used to add and subtract fixed amounts of charge from the sampling capacitor to bring the comparator into a balanced condition. When the comparator is balanced, the conversion is complete and the ADC output code is generated.

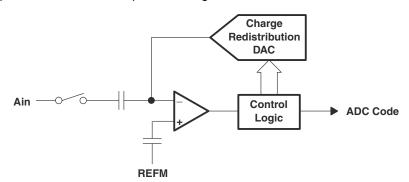


Figure 1. Simplified Model of the Successive-Approximation System

#### **Serial Interface**

INPUT DATA FORMAT				
MSB		LSB		
D15-D12	D11-D0			
Command ID[15:12]	Configuration data field ID[11:0]			

Input data is binary. All trailing blanks can be filled with zeros.

OUTPUT DATA FORMAT READ CFR/FIFO READ			
MSB LS			
D15-D12	D11-D0		
Don't care	Register content or FIFO content OD[11:0]		

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OUTPUT DATA FORMAT CONVERSION			
MSB			
D15-D4	D3-D0		
Conversion result OD[11:0]	Don't care		

The output data format is binary (unipolar straight binary).

#### **Binary**

Zero scale code = 000h, Vcode = VREFM.

Full scale code = FFFh, Vcode = VREFP - 1 LSB

#### **Control and Timing**

#### **Power Up and Initialization Requirements**

- Determine processor type by writing A000h to the TLV2548 (CS must be toggled).
- Configure the device (CS must make a high-to-low transition, then can be held low if in DSP mode; i.e., active FS).

The first conversion after power up or resuming from power down is not valid.

#### Start of the Cycle

- When FS is not used (FS = 1 at the falling edge of  $\overline{CS}$ ), the falling edge of  $\overline{CS}$  is the start of the cycle.
- When FS is used (FS is an active signal from a DSP), the falling edge of FS is the start of the cycle.

#### First 4-MSBs: The Command Register (CMR)

The TLV2548 has a 4-bit command set (see Table 3) plus a 12-bit configuration data field. Most of the commands require only the first 4 MSBs, i.e., without the 12-bit data field.

The valid commands are listed in Table 3.

Table 3. TLV2548 Command Set(1)

SDI D(	15-12) BINARY	COMMAND
0000b	0h	Select analog input channel 0
0001b	1h	Select analog input channel 1
0010b	2h	Select analog input channel 2
0011b	3h	Select analog input channel 3
0100b	4h	Select analog input channel 4
0101b	5h	Select analog input channel 5
0110b	6h	Select analog input channel 6
0111b	7h	Select analog input channel 7
1000b	8h	SW power down (analog + reference)
1001b	9h	Read CFR register data shown as SDO D(11-0)
1010b	Ah plus data	Write CFR followed by 12-bit data, e.g., 0A100h means external reference, short sampling, SCLK/4, single shot, INT
1011b	Bh	Select test, voltage = (REFP+REFM)/2
1100b	Ch	Select test, voltage = REFM
1101b	Dh	Select test, voltage = REFP
1110b	Eh	FIFO read, FIFO contents shown as SDO D(15-4), D(3-0) = 0000
1111b	Fh plus data	Reserved

<sup>(1)</sup> The status of the CFR can be read with a read CFR command when the device is programmed for one–shot conversion mode (CFR D[6,5] = 00).

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#### Configuration

Configuration data is stored in one 12-bit configuration register (CFR) (see Table 4 for CFR bit definitions). Once configured after first power up, the information is retained in the H/W or S/W power down state. When the device is being configured, a write CFR cycle is issued by the host processor. This is a 16-bit write. If the SCLK stops after the first eight bits are entered, then the next eight bits can be taken after the SCLK is resumed.

Table 4. TLV2548 Configuration Register (CFR) Bit Definitions

BIT	DEFINITION	
D11	Reference select 0: External 1: Internal (Tie REFM to analog ground if the internal reference is selected.)	
D10	Internal reference voltage select 0: Internal ref = 4 V 1: internal ref = 2 V	
D9	Sample period select 0: Short sampling 12 SCLKs (1x sampling time) 1: Long sampling 24 SCLKs (2x sampling time)	
D(8,7)	Conversion clock source select 00: Conversion clock = internal OSC 01: Conversion clock = SCLK 10: Conversion clock = SCLK/4 11: Conversion clock = SCLK/2	
D(6,5)	Conversion mode select 00: Single shot mode [FIFO not used, D(1,0) has no effect.] 01: Repeat mode 10: Sweep mode 11: Repeat sweep mode	
D(4,3) <sup>(1)</sup>	Sweep auto sequence select 00: 0-1-2-3-4-5-6-7 01: 0-2-4-6-0-2-4-6 10: 0-0-2-2-4-4-6-6 11: 0-2-0-2-0-2	
D2	EOC/INT - pin function select 0: Pin used as INT 1: Pin used as EOC	
D(1,0)	FIFO trigger level (sweep sequence length) 00: Full (INT generated after FIFO level 7 filled) 01: 3/4 (INT generated after FIFO level 5 filled) 10: 1/2 (INT generated after FIFO level 3 filled) 11: 1/4 (INT generated after FIFO level 1 filled)	

<sup>(1)</sup> These bits only take effect in conversion modes 10 and 11.

#### Sampling

The sampling period starts after the first four input data are shifted in if they are decoded as one of the conversion commands. These are select analog input (channels 0 through 7) and select test (channels 1 through 3).

#### **Normal Sampling**

When the converter is using normal sampling, the sampling period is programmable. It can be 12 SCLKs (short sampling) or 24 SCLKs (long sampling). Long sampling helps when SCLK is faster than 10 MHz or when input source resistance is high.

#### **Extended Sampling**

CSTART - An asynchronous (to the SCLK) signal, via dedicated hardware pin, CSTART, can be used in order to have total control of the sampling period and the start of a conversion. This extended sampling is user defined and is totally independent of SCLK. While CS is high, the falling edge of CSTART is the start of the sampling period and is controlled by the low time of CSTART. The minimum low time for CSTART should be at least equal to the minimum t<sub>(SAMPLE)</sub>. In a select cycle used in mode 01 (REPEAT MODE), CSTART can be started as soon

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as the channel is selected (after the fifth SCLK). In this case the sampling period is not started until CS has become inactive. Therefore the non-overlapped CSTART low time must meet the minimum sampling time requirement. The low-to-high transition of CSTART terminates the sampling period and starts the conversion period. The conversion clock can also be configured to use either internal OSC or external SCLK. This function is useful for an application that requires:

- The use of an extended sampling period to accommodate different input source impedance.
- The use of a faster I/O clock on the serial port but not enough sampling time is available due to the fixed number of SCLKs. This could be due to a high input source impedance or due to higher MUX ON resistance at lower supply voltage.

Once the conversion is complete, the processor can initiate a read cycle by using either the read FIFO command to read the conversion result or by simply selecting the next channel number for conversion. Since the device has a valid conversion result in the output buffer, the conversion result is simply presented at the serial data output. To completely get out of the extended sampling mode,  $\overline{CS}$  must be toggled twice from a high-to-low transition while CSTART is high. The read cycle mentioned above followed by another configuration cycle of the ADC qualifies this condition and successfully puts the ADC back to its normal sampling mode. This can be viewed in Figure 9.

	CONDITIONS	SAMPLE	CONVERT
CSTART	CS = 1 (see Figure 11 and Figure 19)	No sampling clock (SCLK) required. Sampling period is totally controlled by the low time of CSTART. The high-to-low transition of CSTART (when CS = 1) starts the sampling of the analog input signal. The low time of CSTART dictates the sampling period. The low-to-high transition of CSTART ends sampling period and begins the conversion cycle. (Note: this trigger only works when internal reference is selected for conversion modes 01, 10, and 11.)	If the internal clock OSC is selected, a
<del>CS</del>	CSTART = 1 FS = 1	<b>SCLK is required.</b> Sampling period is programmable under normal sampling. When	maximum conversion time of 3.86 μs can be achieved.
FS	CSTART = 1 CS = 0	programmed to sample under short sampling, 12 SCLKs are generated to complete sampling period. 24 SCLKs are generated when programmed for long sampling. A command set to configure the device requires 4 SCLKs thereby extending to 16 or 28 SCLKs respectively before conversion takes place. (Note: Because the ADC only bypasses a valid channel select command, the user can use select channel 0, 0000b, as the SDI input when either $\overline{\text{CS}}$ or FS is used as trigger for conversion. The ADC responds to commands such as SW powerdown, 1000b.)	2) If external SCLK is selected, conversion time is t <sub>conv</sub> = 14 x DIV/f <sub>(SCLK)</sub> , where DIV can be 1, 2, or 4.

**Table 5. Sample and Convert Conditions** 

#### **TLV2548 Conversion Modes**

The TLV2548 has four different conversion modes (mode 00, 01, 10, 11). The operation of each mode is slightly different, depending on how the <u>converter</u> performs the sampling and which host interface is used. The trigger for a conversion can be an active CSTART (extended sampling), CS (normal sampling, SPI interface), or FS (normal sampling, TMS320 DSP interface). When FS is used as the trigger, CS can be held active, i.e. CS does not need to be toggled through the trigger sequence. SDI can be one of the channel select commands, such as SELECT CHANNEL 0. Different types of triggers should not be mixed throughout the <u>repeat and sweep operations</u>. When CSTART is used as the trigger, the conversion starts on the rising edge of CSTART. The minimum low time for CSTART is equal to t<sub>(SAMPLE)</sub>. If an active CS or FS is used as the trigger, the conversion is started after the 16th or 28th SCLK edge. Enough time (for conversion) should be allowed between consecutive triggers so that no conversion is terminated prematurely.

#### One Shot Mode (Mode 00)

One shot mode (mode 00) does not use the FIFO, and the EOC is generated as the conversion is in progress (or INT is generated after the conversion is done).

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#### Repeat Mode (Mode 01)

Repeat mode (mode 01) uses the FIFO. This mode setup requires configuration cycle and channel select cycle. Once the programmed FIFO threshold is reached, the FIFO must be read, or the data is lost when the sequence starts over again with the SELECT cycle and series of triggers. No configuration is required except for re-selecting the channel unless the operation mode is changed. This allows the host to set up the converter and continue monitoring a fixed input and come back to get a set of samples when preferred.

Triggered by CSTART: The first conversion can be started with a select cycle or CSTART. To do so, the user can issue CSTART during the select cycle, immediately after the 4-bit channel select command. The first sample started as soon as the select cycle is finished (i.e., CS returns to 1). If there is enough time (2 µs) left between the SELECT cycle and the following CSTART, a conversion is carried out. In this case, you need one less trigger to fill the FIFO. Succeeding samples are triggered by CSTART.

#### Sweep Mode (Mode 10)

Sweep mode (mode 10) also uses the FIFO. Once it is programmed in this mode, all of the channels listed in the selected sweep sequence are visited in sequence. The results are converted and stored in the FIFO. This sweep sequence may not be completed if the FIFO threshold is reached before the list is completed. This allows the system designer to change the sweep sequence length. Once the FIFO has reached its programmed threshold, an interrupt (INT) is generated. The host must issue a read FIFO command to read and clear the FIFO before the next sweep can start.

#### Repeat Sweep Mode (Mode 11)

Repeat sweep mode (mode 11) works the same way as mode 10 except the operation has an option to continue even if the FIFO threshold is reached. Once the FIFO has reached its programmed threshold, an interrupt (INT) is generated. Then two things may happen:

- 1. The host may choose to act on it (read the FIFO) or ignore it. If the next cycle is a read FIFO cycle, all of the data stored in the FIFO is retained until it has been read in order.
- 2. If the next cycle is not a read FIFO cycle, or another CSTART is generated, all of the content stored in the FIFO is cleared before the next conversion result is stored in the FIFO, and the sweep is continued.

**CONVERSION CFR SAMPLING OPERATION** MODE D(6,5) **TYPE** Single conversion from a selected channel CS or FS to start select/sampling/conversion/read Normal One INT or EOC generated after each conversion Host must serve INT by selecting channel, and converting and reading the previous output. 00 One shot Single conversion from a selected channel CS to select/read **CSTART** to start sampling and conversion Extended One INT or EOC generated after each conversion Host must serve INT by selecting next channel and reading the previous

Table 6. TLV2548 Conversion Mode<sup>(1)</sup> (2) (3)

 <sup>(1)</sup> Programming the EOC/INT pin as the EOC signal works for mode 00 only. The other three modes automatically generate an INT signal irrespective of how EOC/INT is programmed.
 (2) Extended sampling mode using CSTART as the trigger only works when internal reference is selected for conversion modes 01, 10, and

<sup>(2)</sup> Extended sampling mode using CSTART as the trigger only works when internal reference is selected for conversion modes 01, 10, and 11.

<sup>(3)</sup> When using CSTART to sample in extended mode, the falling edge of the next CSTART trigger should occur no more than 2.5 µs after the falling CS edge (or falling FS edge if FS is active) of the channel select cycle. This is to prevent an ongoing conversion from being canceled.

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## Table 6. TLV2548 Conversion Mode (1) (2) (3) (continued)

CONVERSION MODE	CFR D(6,5)	SAMPLING TYPE	OPERATION
Repeat	01	Normal	<ul> <li>Repeated conversions from a selected channel</li> <li>CS or FS to start sampling/conversion</li> <li>One INT generated after FIFO is filled up to the threshold</li> <li>Host must serve INT by either 1) (FIFO read) reading out all of the FIFO contents up to the threshold, then repeat conversions from the same selected channel or 2) writing another command(s) to change the conversion mode. If the FIFO is not read when INT is served, it is cleared.</li> </ul>
		Extended	Same as normal sampling except CSTART starts each sampling and conversion when CS is high.
Sweep	10	Normal	<ul> <li>One conversion per channel from a sequence of channels</li> <li>CS or FS to start sampling/conversion</li> <li>One INT generated after FIFO is filled up to the threshold</li> <li>Host must serve INT by (FIFO read) reading out all of the FIFO contents up to the threshold, then write another command(s) to change the conversion mode.</li> </ul>
		Extended	Same as normal sampling except CSTART starts each sampling and conversion when CS is high.
Repeat sweep	11	Normal	Repeated conversions from a sequence of channels  Tellow or FS to start sampling/conversion  One INT generated after FIFO is filled up to the threshold  Host must serve INT by either 1) (FIFO read) reading out all of the FIFO contents up to the threshold, then repeat conversions from the same selected channel or 2) writing another command(s) to change the conversion mode. If the FIFO is not read when INT is served it is cleared.
		Extended	Same as normal sampling except CSTART starts each sampling and conversion when CS is high.

#### **Timing Diagrams**

The timing diagrams can be categorized into two major groups: non-conversion and conversion. The non-conversion cycles are read and write (configuration). None of these cycles carry a conversion. Conversion cycles are those four modes of conversion.

#### Read Cycle (Read FIFO or Read CFR)

#### Read CFR Cycle

The read command is decoded in the first four clocks. SDO outputs the contents of the CFR after the fourth SCLK. This command works only when the device is programmed in the single shot mode (mode 00).

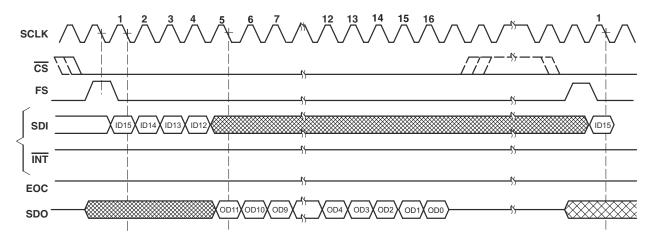


Figure 2. TLV2548 Read CFR Cycle (FS active)



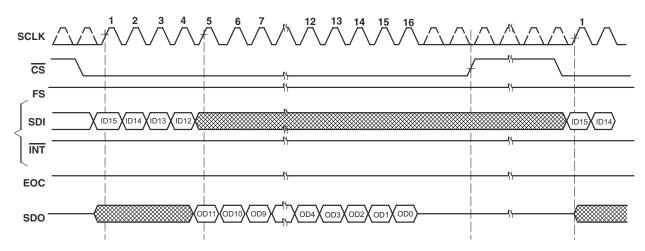
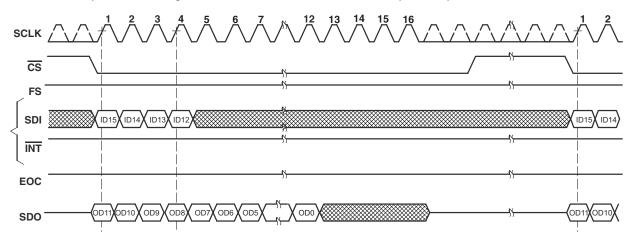


Figure 3. TLV2548 Read CFR Cycle (FS = 1)

#### FIFO Read Cycle

The first command in the active cycle after  $\overline{\text{INT}}$  is generated, if the FIFO is used, is assumed as the FIFO read command. The first FIFO content is output immediately before the command is decoded. If this command is not a FIFO read, then the output is terminated but the first data in the FIFO is retained until a valid FIFO read command is decoded. Use of more layers of the FIFO reduces the time taken to read multiple data. This is because the read cycle does not generate EOC or  $\overline{\text{INT}}$ , nor does it carry out any conversion.



These devices can perform continuous FIFO read cycles (FS = 1) controlled by SCLK; SCLK can stop between each 16 SCLKs.

Figure 4. TLV2548 FIFO Read Cycle (FS = 1)



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#### Write Cycle (Write CFR)

The write cycle is used to write to the configuration register CFR (with 12-bit register content). The write cycle does not generate an EOC or INT, nor does it carry out any conversion (see power up and initialization requirements).

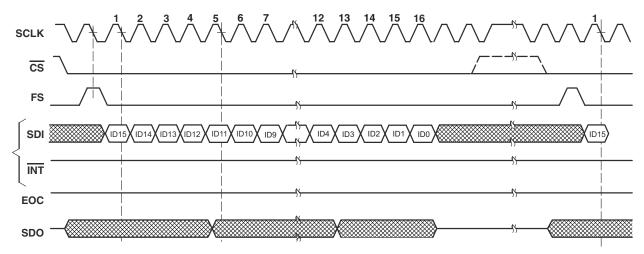


Figure 5. TLV2548 Write Cycle (FS Active)

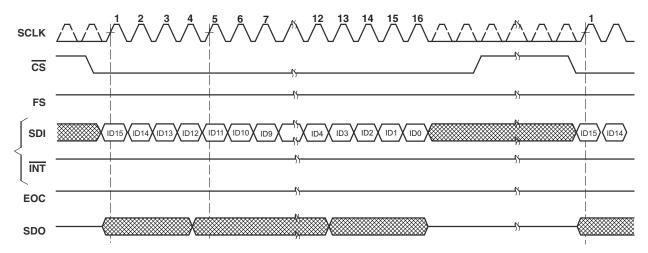


Figure 6. TLV2548 Write Cycle (FS = 1)



#### **Conversion Cycles**

#### **DSP/Normal Sampling**

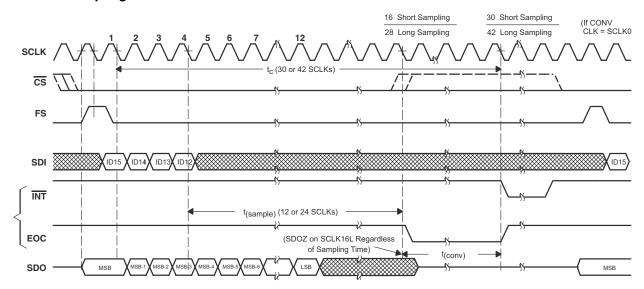


Figure 7. Mode 00 Single Shot/Normal Sampling (FS Signal Used)

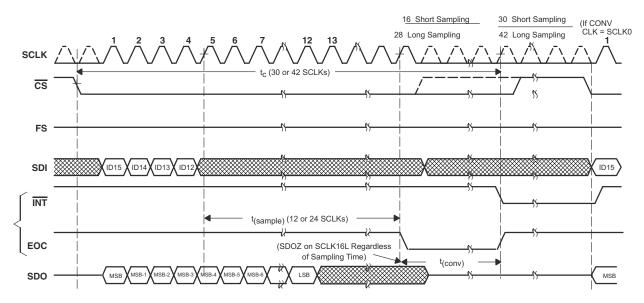
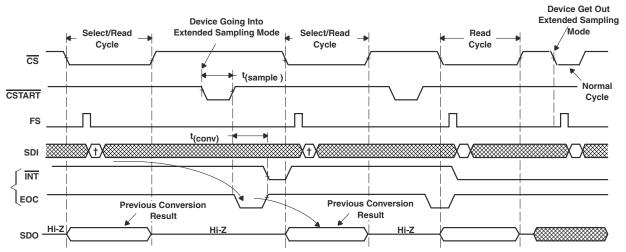


Figure 8. Mode 00 Single Shot/Normal Sampling (FS = 1, FS Signal Not Used)



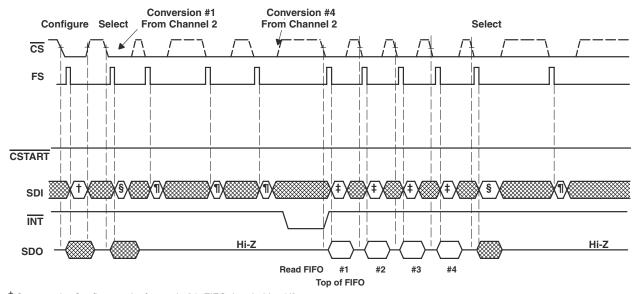
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<sup>†</sup> This is one of the single shot commands. Conversion starts on next rising edge of CSTART.

Figure 9. Mode 00 Single Shot/Extended Sampling (FS Signal Used, FS Pin Connected to TMS320 DSP)

#### Modes Using the FIFO: Modes 01, 10, 11 Timing



<sup>†</sup>Command = Configure write for mode 01, FIFO threshold = 1/2

Figure 10. TLV2548 Mode 01 DSP Serial Interface (Conversions Triggered by FS)

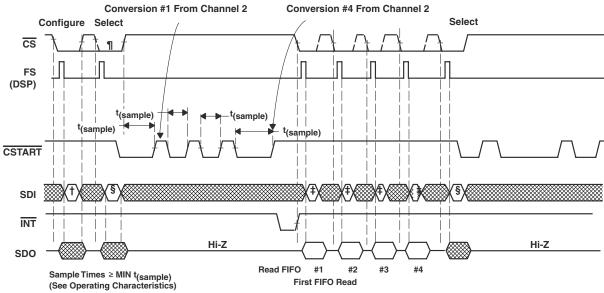
<sup>‡</sup>Command = Read FIFO, first FIFO read

<sup>§</sup> Command = Select ch2.

 $<sup>\</sup>P$  Use any channel select command to trigger SDI input.

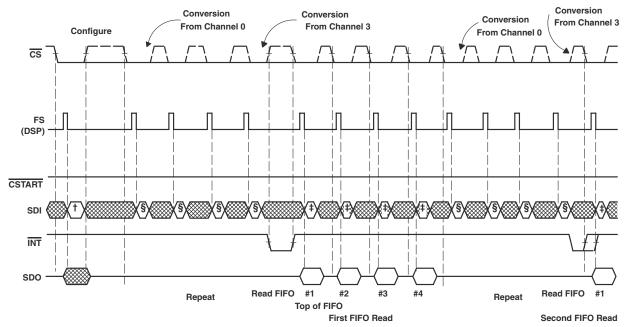
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<sup>†</sup> Command = Configure write for mode 01, FIFO threshold = 1/2

Figure 11. TLV2548 Mode 01 μp/DSP Serial Interface (Conversions Triggered by CSTART)



<sup>†</sup> Command = Configure write for mode 10 or 11, FIFO threshold = 1/2, sweep seq = 0-1-2-3.

Figure 12. TLV2548 Mode 10/11 DSP Serial Interface (Conversions Triggered by FS)

<sup>‡</sup>Command = Read FIFO, first FIFO read

<sup>§</sup> Command = Select ch2.

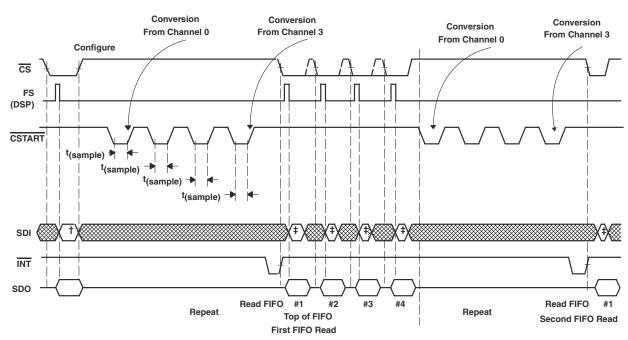
Minimum CS low time for select cycle is 6 SCLKs. The same amount of time is required between FS low to CSTART for proper channel decoding. The low time of CSTART, not overlapped with CS low time, is the valid sampling time for the select cycle (see Figure 19).

<sup>‡</sup>Command = Read FIFO

<sup>§</sup> Use any channel select command to trigger SDI input.

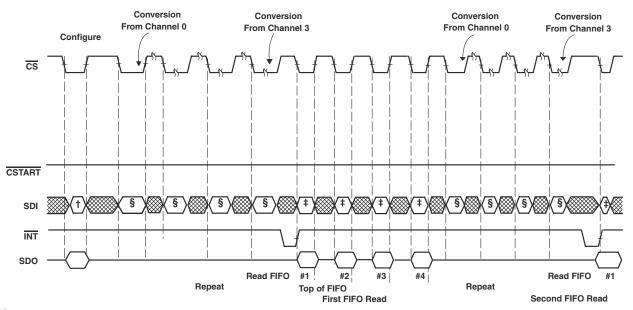


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<sup>†</sup> Command = Configure write for mode 10 or 11, FIFO threshold = 1/2, sweep seq = 0-1-2-3.

Figure 13. TLV2548 Mode 10/11 DSP Serial Interface (Conversions Triggered by CSTART)



<sup>†</sup> Command = Configure write for mode 10 or 11, FIFO threshold = 1/2, sweep seq = 0-1-2-3.

Figure 14. TLV2548 Mode 10/11 μp Serial Interface (Conversions Triggered by CS)

<sup>‡</sup>Command = Read FIFO

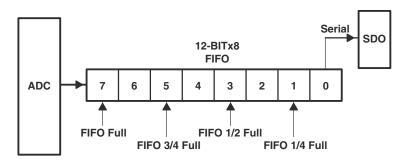
<sup>‡</sup>Command = Read FIFO

<sup>§</sup> Use any channel select command to trigger SDI input.

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#### FIFO Operation



**FIFO Threshold Pointer** 

Figure 15. TLV2548 FIFO

The device has an eight-layer FIFO that can be programmed for different thresholds. An interrupt is sent to the host after the pre-programmed threshold is reached. The FIFO can be used to store data from either a fixed channel or a series of channels based on a pre-programmed sweep sequence. For example, an application may require eight measurements from channel 3. In this case, the FIFO is filled with eight data sequentially taken from channel 3. Another application may require data from channel 0, channel 2, channel 4, and channel 6 in an orderly manner. Therefore, the threshold is set for 1/2 and the sweep sequence 0-2-4-6-0-2-4-6 is chosen. An interrupt is sent to the host as soon as all four data are in the FIFO.

In single shot mode, the FIFO automatically uses a 1/8 FIFO depth. Therefore the CFR bits (D1,0) controlling FIFO depth are don't care.

#### **SCLK and Conversion Speed**

There are two ways to adjust the conversion speed.

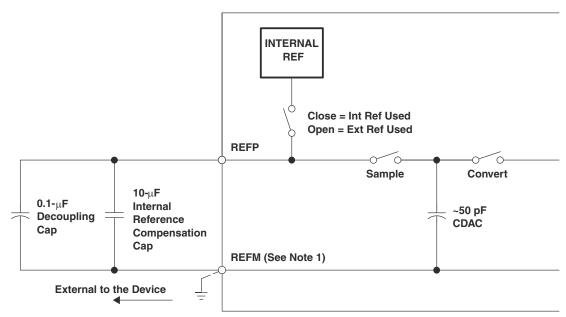
- The SCLK can be used as the source of the conversion clock to get the highest throughput of the device.
- The minimum onboard OSC is 3.6 MHz and 14 conversion clocks are required to complete a conversion (corresponding 3.86- $\mu$ s conversion time). The devices can operate with an SCLK up to 20 MHz for the supply voltage range specified. When a more accurate conversion time is desired, the SCLK can be used as the source of the conversion clock. The clock divider provides speed options appropriate or an application where a high speed SCLK is used for faster I/O. The total conversion time is 14 x (DIV/f<sub>SCLK</sub>) where DIV is 1, 2, or 4. For example a 20-MHz SCLK with the divide by 4 option produces a 14 x (4/20 M) = 2.8- $\mu$ s conversion time. When an external serial clock (SCLK) is used as the source of the conversion clock, the maximum equivalent conversion clock (f<sub>SCLK</sub>/DIV) should not exceed 6 MHz.
- Autopower down can be used to slow down the device at a reduced power consumption level. This mode is
  always used by the converter. If the device is not accessed (by CS or CSTART), the converter is powered
  down to save power. The built-in reference is left on in order to quickly resume operation within one half
  SCLK period. This provides unlimited choices to trade speed with power savings.

#### Reference Voltage

The device has a built-in reference with a programmable level of 2 V or 4 V. If the internal reference is used, REFP is set to 2 V or 4 V and REFM should be connected to the analog ground of the converter. An external reference can also be used through two reference input pins, REFP and REFM, if the reference source is programmed as external. The voltage levels applied to these pins establish the upper and lower limits of the analog inputs to produce a full-scale and zero-scale reading respectively. The values of REFP, REFM, and the analog input should not exceed the positive supply or be lower than GND consistent with the specified absolute maximum ratings. The digital output is at full scale when the input signal is equal to or higher than REFP and at zero when the input signal is equal to or lower than REFM.

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#### Reference Block Equivalent Circuit



- A. If internal reference is used, tie REFM to analog ground and install a 10-μF (or 4.7-μF) internal reference compensation capacitor between REFP and REFM to store the charge as shown in the figure above.
- B. If external reference is used, the 10-μF (internal reference compensation) capacitor is optional. REFM can be connected to external REFM or AGND.
- C. Internal reference voltage drift, due to temperature variations, is approximately ±10 mV about the nominal 2 V (typically) from -10°C to 100°C. The nominal value also varies approximately ±50 mV across devices.
- D. Internal reference leakage during low ON time: Leakage resistance is on the order of 100 MΩ or more. This means the time constant is about 1000 s with 10-μF compensation capacitance. Since the REF voltage does not vary much, the reference comes up quickly after resuming from auto power down. At power up and power down the internal reference sees a glitch of about 500 μV when 2-V internal reference is used (1 mV when 4-V internal reference is used). This glitch settles out after about 50 μs.

Figure 16. Reference Block Equivalent Circuit

#### **Power Down**

The device has three power-down modes.

#### **Autopower-Down Mode**

The device enters the autopower-down state at the end of a conversion.

In autopower-down, the power consumption reduces to about 1 mA when an internal reference is selected. The built-in reference is still on to allow the device to resume quickly. The resumption is fast enough (within 0.5 SCLK) for use between cycles. An active  $\overline{\text{CS}}$ , FS, or  $\overline{\text{CSTART}}$  resumes the device from power-down state. The power current is 1  $\mu$ A when an external reference is programmed and SCLK stops.

#### Hardware/Software Power-Down Mode

Writing 8000h to the device puts the device into a software power-down state, and the entire chip (including the built-in reference) is powered down. For a hardware power down, the dedicated PWDN pin provides another way to power down the device asynchronously. These two power-down modes power down the entire device including the built-in reference to save power. The power-down current is reduced to about 1 µA as the SCLK is stopped.

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An active  $\overline{\text{CS}}$ , FS, or  $\overline{\text{CSTART}}$  restores the device. There is no time delay when an external reference is selected. However, if an internal reference is used, it takes about 20 ms to warm up. Deselect  $\overline{\text{PWDN}}$  pin to remove the device from the hardware power-down state. This requires about 20 ms to warm up if an internal reference is also selected.

The configuration register is not affected by any of the power-down modes but the sweep operation sequence has to be started over again. All FIFO contents are cleared by the power-down modes.

#### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted) (1)

		VALUE	UNIT
	Supply voltage range, GND to V <sub>CC</sub>	-0.3 to 6.5	V
	Analog input voltage range	$-0.3$ to $V_{CC} + 0.3$	V
	Reference input voltage	V <sub>CC</sub> + 0.3	V
	Digital input voltage range	$-0.3$ to $V_{CC} + 0.3$	V
TJ	Operating virtual junction temperature range	-55 to 150	°C
T <sub>A</sub>	Operating free-air temperature range	-55 to 125	°C
T <sub>stg</sub>	Storage temperature range	-65 to 150	°C
	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260	°C

<sup>(1)</sup> Stresses beyond those listed under the absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under the recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATINGS**

PACKAGE	T <sub>A</sub> < 25°C	DERATING FACTOR	T <sub>A</sub> = 125°C
	POWER RATING	ABOVE $T_A = 25^{\circ}C^{(1)}$	POWER RATING
20 PW	977 mW	7.8 mW/°C	195 mW

<sup>(1)</sup> This is the inverse of the traditional junction-to-ambient thermal resistance (R<sub>θJA</sub>). Thermal resistance is not production tested and the values given are for informational purposes only.

#### RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		3	3.3	5.5	V
	Analog input voltage <sup>(1)</sup>		0		$V_{CC}$	V
V <sub>IH</sub>	High level control input vo	ltage	2.1			V
V <sub>IL</sub>	Low-level control input vo	oltage			0.6	V
t <sub>d(CSL-FSH)</sub>	Delay time, delay from CS (see Figure 17).	s falling edge to FS rising edge	0.5			SCLKs
t <sub>d</sub> (SCLK-CSH)		th SCLK falling edge to $\overline{CS}$ 7th rising edge (FS is active) 220).	0.5			SCLKs
t <sub>su(FSH</sub> -SCLKL	Setup time, FS rising edg (see Figure 17).	e before SCLK falling edge	20			ns
t <sub>h(FSH</sub> -SCLKL)	Hold time, FS hold high a (see Figure 17).	fter SCLK falling edge	30			ns
t <sub>wH(CS)</sub>	Pulse width, CS high time	(see Figure 17 and Figure 20).	100			ns
t <sub>wH(FS)</sub>	Pulse width, FS high time	(see Figure 17).	0.75		1	SCLKs
SCLK cycle time $V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$			67		10000	
t <sub>c(SCLK)</sub>	(see Figure 17 and Figure 20).	V <sub>CC</sub> = 4.5 V to 5.5V	50		10000	ns

<sup>(1)</sup> When binary output format is used, analog input voltages greater than that applied to REFP convert as all ones (111111111111), while input voltages less than that applied to REFM convert as all zeros (000000000000). The device is functional with reference down to 1 V. (VREFP - VREFM - 1); however, the electrical specifications are no longer applicable.

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## **RECOMMENDED OPERATING CONDITIONS (continued)**

over operating free-air temperature range (unless otherwise noted)

				MIN	NOM	MAX	UNIT
	Pulse width, SCLK low	V <sub>CC</sub> = 4.5 V		22			
t <sub>wL(SCLK)</sub>	time (see Figure 17 and Figure 20)	V <sub>CC</sub> = 3.0 V		27			ns
	Pulse width, SCLK high	V <sub>CC</sub> = 4.5 V		22			
t <sub>wH(SCLK)</sub>	time (see Figure 17 and Figure 20)	V <sub>CC</sub> = 3.0 V		27			ns
t <sub>su(DI-SCLK</sub>	Setup time, SDI valid before active) or the rising edge of (see and Figure 20).		of SCLK (FS is	25			ns
t <sub>h(DI-SCLK)</sub>	Hold time, SDI hold valid a is active) or the rising edge (see Figure 17).			5			ns
$t_{d(CSL-DOV)}$	Delay time, delay from $\overline{\text{CS}}$ (see Figure 17 and Figure		SDO valid			25	ns
t <sub>d(FSL-DOV)</sub>	Delay time, delay from FS (see Figure 17).	falling edge to	SDO valid			25	ns
	Delay time, delay from	V <sub>CC</sub> = 5.5 V	SDO = 0 pF		0.5 SCLK + 5		
	SCLK falling edge (FS is active) or SCLK rising edge (FS=1) to SDO valid (see Figure 17 and		SDO = 60 pF			0.5 SCLK + 24	
			SDO = 5 pF	(	).5 SCLK + 12		
t <sub>d</sub> (SCLK-DOV)	Figure 20). For a date code later than xxx, see the Data Code Information section, item 3.	V <sub>CC</sub> = 3.0 V	SDO = 25 pF			0.5 SCLK + 33	ns
t <sub>d</sub> (SCLK-EOCL)	Delay time, delay from 17th active) or the 16th falling e edge (see Figure 17 and Figure	dge (FS=1) to E			45		ns
$t_{d(SCLK-INTL)}$	Delay time, delay from 16th falling edge (FS =1) or from to INT falling edge (when F	n the 17th rising	g edge SCLK	Min t <sub>(conv)</sub>			μs
$\begin{array}{l} t_{d(CSL-INTH)} \\ or \\ t_{d(FSH-INTH)} \end{array}$	Delay time, delay from $\overline{CS}$ to $\overline{INT}$ rising edge (see Fig and Figure 20).					50	ns
$t_{d(CSH-CSTARTL)}$	Delay time, delay from $\overline{\text{CS}}$ edge (see Figure 18 and F		CSTART falling	100			ns
t <sub>d(CSTARTH</sub> EOCL)	Delay time, delay from CS falling edge (see Figure 18					50	ns
t <sub>wL(CSTART)</sub>	Pulse width, CSTART low Figure 19).	time (see Figure	e 18 and	Min t <sub>(sample)</sub>			μs
t <sub>d(CSTARTH</sub> -CSTARTL)	Delay time, delay from CS falling edge (see Figure 19		ge to CSTART	Max t <sub>(conv)</sub>			μs
$t_{d(CSTARTH-INTL)}$	Delay time, delay from CS falling edge (see Figure 18		,		Max t <sub>(conv)</sub>		μs
T <sub>A</sub>	Operating free-air tempera	iture		-55		125	°C

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over operating free-air temperature range,  $V_{CC} = V_{REFP} = 3 \text{ V}$  to 5.5 V,  $V_{REFM} = 0 \text{ V}$ , SCLK frequency = 20 MHz at 5 V,

15 MHz at 3 V (unless otherwise noted)

	PARAMETER	TES	T COND	TIONS	MIN	TYP (1)	MAX	UNIT
\/	High lovel output voltage	$V_{CC} = 5.5 \text{ V}, I_{OH} =$	-0.2 mA a	at 30 pF load	2.4			V
V <sub>OH</sub>	High-level output voltage	$V_{CC} = 3.0 \text{ V}, I_{OH} = 6.0 \text{ V}$	–20 µA a	t 30 pF load	V <sub>CC</sub> -0.2			V
V	Low level cutout voltage	$V_{CC} = 5.5 \text{ V}, I_{OL} = 0$	0.8 mA a	: 30 pF load			0.4	V
V <sub>OL</sub>	Low-level output voltage	$V_{CC} = 3.0 \text{ V}, I_{OL} = 2$	20 μA at	30 pF load			0.1	V
	Off-state output current	$V_O = V_{CC}$	CS = V	СС			2.5	
l <sub>OZ</sub>	(high-impedance-state)	V <sub>O</sub> = 0	$\overline{CS} = V$	СС	-2.5			μA
I <sub>IH</sub>	High-level input current	$V_I = V_{CC}$	•			0.005	2.5	μΑ
I <sub>IL</sub>	Low-level input current	$V_I = 0 V$				-0.005	2.5	μΑ
		CS at 0 V, Ext ref	V <sub>CC</sub> = 4	1.5 V to 5.5 V			2	
	Operating supply current,	CS at 0 V, Ext ref	$V_{CC} = 3$	3.0 V to 3.3 V			1	
	normal short sampling	<u> </u>	V <sub>CC</sub> = 4	1.5 V to 5.5 V			2.4	
		CS at 0 V, Int ref	$V_{CC} = 3$	3.0 V to 3.3 V			1.7	1
Icc		<u> </u>	V <sub>CC</sub> = 4	1.5 V to 5.5 V		1.1		mA
	Operating supply current,	CS at 0 V, Ext ref	V <sub>CC</sub> = 3.0 V to 3.3 V			1		
	extended sampling	CS at 0 V, Int ref	V <sub>CC</sub> = 4	1.5 V to 5.5 V		2.1		
		CS at 0 v, int rer	$V_{CC} = 3$	3.0 V to 3.3 V		1.6		
	Power down supply current	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V, Ext clo	ock		1		
I <sub>CC(PD)</sub>	for all digital inputs, $0 \le V_1 \le 0.3 \text{ V or}$ $V_1 \ge \text{VCC} - 0.3 \text{ V, SCLK} = 0$	V <sub>CC</sub> = 2.7 V to 3.3	V, Ext clo	ock		1		μΑ
	Auto power–down current	V <sub>CC</sub> = 4.5 V to 5.5	V, Ext clo	ck, Ext ref		1.0(2)		
I <sub>CC(AUTOPWDN)</sub>	for all digital inputs, $0 \le V_1 \le 0.3 \text{ V or}$ $V_1 \ge V_{CC} - 0.3 \text{ V, SCLK} = 0$	V <sub>CC</sub> = 2.7 V to 3.3		1.0 <sup>(3)</sup>		μΑ		
	Selected channel leakage	Selected channel a	t Vcc				2.5	
	current	Selected channel a					2.5	μΑ
	Maximum static analog reference current into REFP (use external reference)	VREFP = V <sub>CC</sub> = 5.9	5 V, VRE	FM = GND		1		μΑ
	lanut conseitance	Analog inputs				45	50	
C <sub>i</sub>	Input capacitance	Control Inputs				5	25	pF
7	Innut MIIV ON registance	V <sub>CC</sub> = 4.5 V					500	Ω
Z <sub>i</sub>	Input MUX ON resistance	V <sub>CC</sub> = 2.7 V					600	12
AC SPECIFICA	ATIONS							
SINAD	Signal-to-noise ratio + distortion	f <sub>I</sub> = 12 kHz at 200 k	(SPS		65	71		dB
		T <sub>A</sub> = -55°C			-82	-73		
THD	Total harmonic distortion	f <sub>I</sub> = 12 kHz at 200 KSPS All other temperatures			-82	<b>–</b> 75	dB	
ENOB	Effective number of bits	f <sub>I</sub> = 12 kHz at 200 KSPS				11.6		Bits
SFDR	Spurious free dynamic range	f <sub>I</sub> = 12 kHz at 200 k	(SPS			-84	-75	dB
Analog Input								
	Full-power bandwidth, -3 dB		-			1		MHz
	Full-power bandwidth, -1 dB			500		kHz		

**NSTRUMENTS** 

<sup>(1)</sup> All typical values are at  $V_{CC} = 5$  V,  $T_A = 25^{\circ}$ C. (2) 1.2 mA if internal reference is used, 165  $\mu$ A if internal clock is used. (3) 0.8 mA if internal reference is used, 116  $\mu$ A if internal clock is used.

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## **ELECTRICAL CHARACTERISTICS (continued)**

over operating free-air temperature range,  $V_{CC} = V_{REFP} = 3 \text{ V}$  to 5.5 V,  $V_{REFM} = 0 \text{ V}$ , SCLK frequency = 20 MHz at 5 V, 15 MHz at 3 V (unless otherwise noted)

	PARAMETER	TES	ST CONDITIONS	MIN	TYP (1)	MAX	UNIT
	SPECIFICATIONS <sup>(4)</sup> ) µF between REFP and						
REFP	Positive reference input voltage	V <sub>CC</sub> = 2.7 V to 5.5	V	2		V <sub>CC</sub>	V
REFM	Negative reference input voltage	V <sub>CC</sub> = 2.7 V to 5.5	0		2	V	
			$\overline{\text{CS}} = 1$ , $\text{SCLK} = 0$ , (off)	100			ΜΩ
	Defense and leaved in a selection	$V_{CC} = 5.5 \text{ V}$	$\overline{\text{CS}} = 0$ , $\begin{array}{c} \text{SCLK} = 20 \text{ MHz} \\ \text{(on)} \end{array}$	20	25		kΩ
	Reference Input impedance		$\overline{\text{CS}} = 1$ , $\text{SCLK} = 0$ (off)	100			ΜΩ
		V <sub>CC</sub> = 2.7 V	$\overline{\text{CS}} = 0$ , $\begin{array}{c} \text{SCLK} = 15 \text{ MHz} \\ \text{(on)} \end{array}$	20	25		kΩ
REFP-REFM	Reference Input voltage difference	V <sub>CC</sub> = 2.7 V to 5.5	V	2		V <sub>CC</sub>	V
		V <sub>CC</sub> = 5.5 V	VREF SELECT = 4 V	3.85	4	4.15	
REFP-REFM	Internal reference voltage	V <sub>CC</sub> = 5.5 V	VREF SELECT = 2 V	1.925	2	2.075	V
		V <sub>CC</sub> = 2.7 V	VREF SELECT = 2 V	1.925	2	2.075	
	Internal reference start-up time	V <sub>CC</sub> = 5.5 V, 2.7 V	with 10 μF compensation cap		20		ms
	Internal reference temperature coefficient	V <sub>CC</sub> = 2.7 V to 5.5	V		16	40 <sup>(5)</sup>	PPM/°C

<sup>(4)</sup> Specified by design.(5) Specified by design.

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#### **OPERATING CHARACTERISTICS**

over operating free-air temperature range,  $V_{CC} = V_{REFP} = 3 \text{ V}$  to 5.5 V,  $V_{REFM} = 0 \text{ V}$ , SCLK frequency = 20 MHz at 5 V, 15 MHz at 3 V (unless otherwise noted)

	PARAMETI	ΕR	TEST	CONDITIONS	MIN	TYP (1)	MAX	UNIT
EL	Integral linearity error (I	NL) <sup>(2)</sup>					±1.2	LSB
ED	Differential linearity erro	or (DNL)	See (3)			±1.2	LSB	
EO Offset error (4)			See (3)	T <sub>A</sub> = 25°C and 125°C	-4		6	LSB
				$T_A = -55$ °C	-4		6.2	
EFS Full scale error (4)			See (3)	T <sub>A</sub> = 25°C and 125°C	-4		6	LSB
				$T_A = -55$ °C	-4		7.6	
			SDI = B000h		800h (2048D)			
	Self-test output code (5	i)	SDI = C000h		000h (0D)			
			SDI = D000h			FFFh (4095D)		
		Internal OSC				3.2	4.5	
t <sub>(conv)</sub>	t <sub>(conv)</sub> Conversion time External SCLK				(	14 x DIV) / f <sub>SCLK</sub>		μs
t <sub>(sample)</sub>	With a maximum of 1-kW input source impedance				600			ns

<sup>(1)</sup> All typical values are at  $T_A = 25$ °C.

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<sup>(2)</sup> Linear error is the maximum deviation from the best straight line through the A/D transfer characteristics.

<sup>(3)</sup> Analog input voltages greater than that applied to REFP convert as all ones (11111111111), while input voltages less than that applied to REFM convert as all zeros (000000000000).

<sup>(4)</sup> Zero error is the difference between 000000000000 and the converted output for zero input voltage: full-scale error is the difference between 11111111111 and the converted output for full-scale input voltage.

<sup>(5)</sup> Both the input data and the output codes are expressed in positive logic.



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# PARAMETER MEASUREMENT INFORMATION

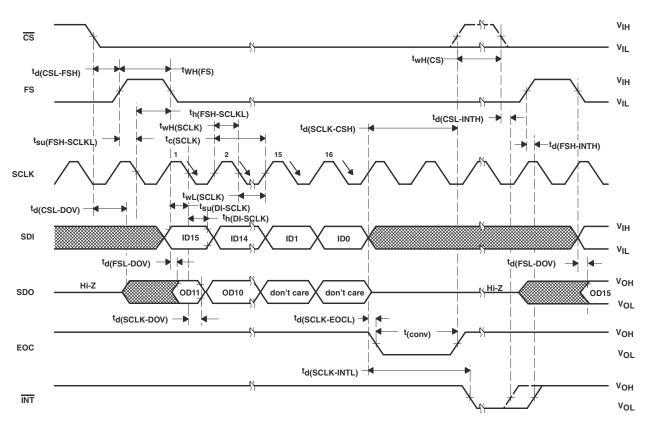
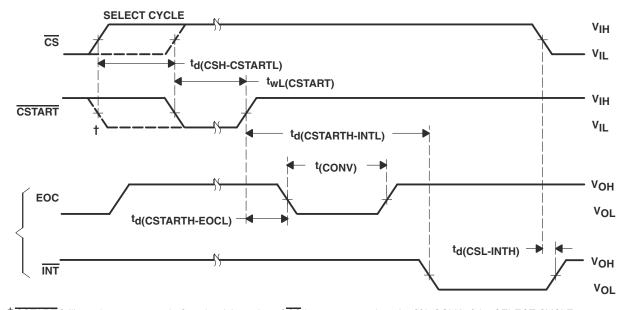


Figure 17. Critical Timing, DSP Mode (Normal Sampling, FS is Active)

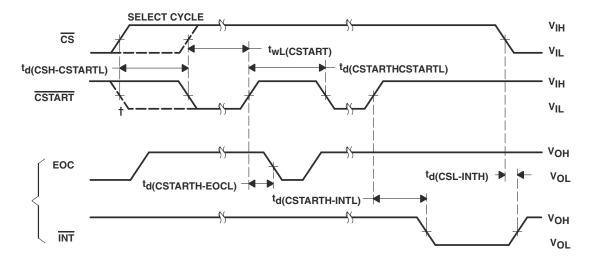


<sup>†</sup> CSTART falling edge may come before the rising edge of CS but no sooner than the fifth SCLK of the SELECT CYCLE.

Figure 18. Critical Timing (Extended Sampling, Single Shot)

# TEXAS INSTRUMENTS

#### PARAMETER MEASUREMENT INFORMATION (continued)



<sup>†</sup> CSTART falling edge may come before the rising edge of CS but no sooner than the fifth SCLK of the SELECT CYCLE. In this case, the actual sampling time is measured from the rising edge CS to the rising edge of CSTART.

Figure 19. Critical Timing (Extended Sampling, Repeat/Sweep/Repeat Sweep)

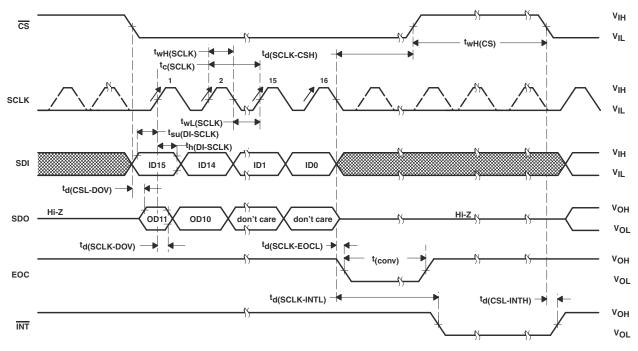
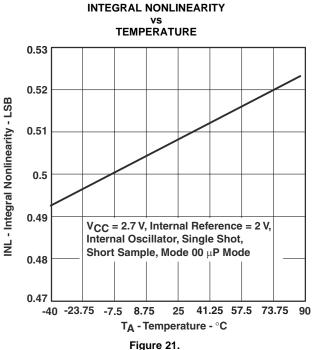


Figure 20. Critical Timing, Microprocessor Mode (Normal Sampling, FS = 1)



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#### TYPICAL CHARACTERISTICS



# 0.6 0.595 INL - Integral Nonlinearity - LSB 0.59 0.585 0.58 0.575 0.57 0.565 0.56 -40 -23.75 -7.5 8.75

Figure 22.

INTEGRAL NONLINEARITY

**TEMPERATURE** 

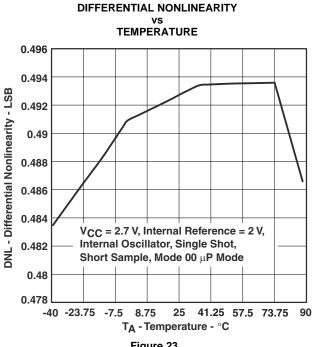
V<sub>CC</sub> = 5.5 V, Internal Reference = 2 V,

T<sub>A</sub> - Temperature - °C

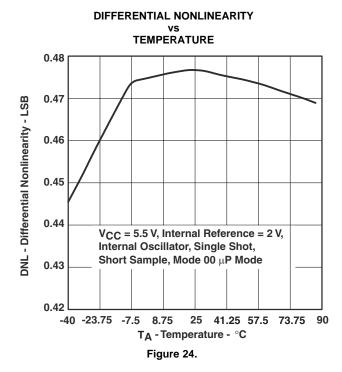
25 41.25 57.5 73.75 90

Internal Oscillator, Single Shot,

Short Sample, Mode 00  $\mu\text{P}$  Mode



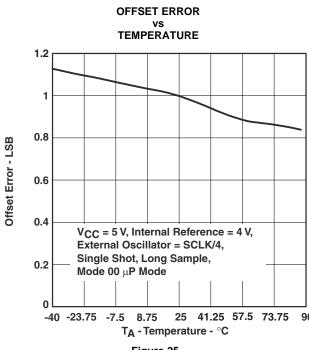




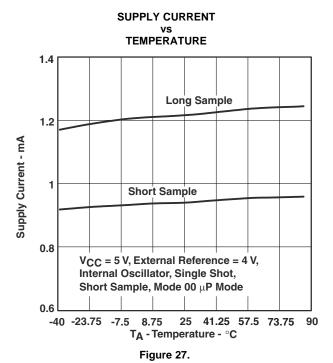
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# **NSTRUMENTS**

#### TYPICAL CHARACTERISTICS (continued)



#### Figure 25.



**GAIN ERROR** vs **TEMPERATURE** 0.5 0 -0.5 Gain Error - LSB -1 -1.5 V<sub>CC</sub> = 5 V, Internal Reference = 4 V, External Oscillator = SCLK/4, Single Shot, Long Sample, -2 Mode 00 µP Mode -2.5 -40 -23.75 -7.5 8.75 25 41.25 57.5 73.75 90 T<sub>A</sub> - Temperature - °C

Figure 26.

# **POWER DOWN CURRENT** TEMPERATURE

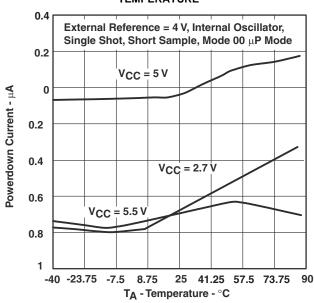


Figure 28.



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# TYPICAL CHARACTERISTICS (continued)

# INTEGRAL NONLINEARITY vs

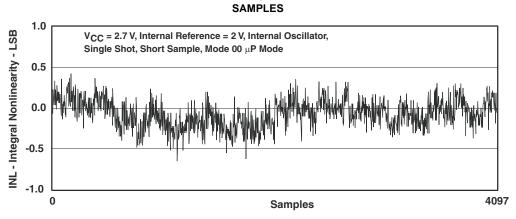
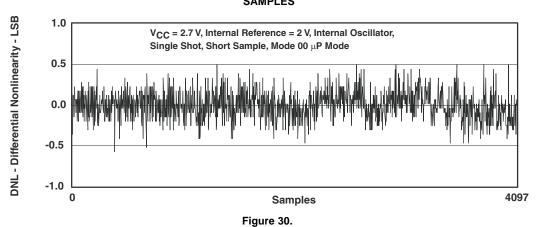


Figure 29.

# DIFFERENTIAL NONLINEARITY vs SAMPLES



# INTEGRAL NONLINEARITY vs SAMPLES

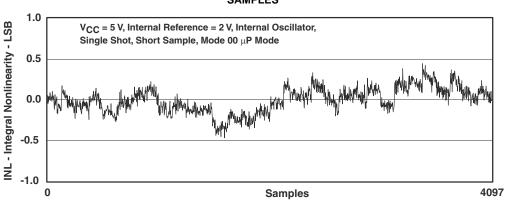


Figure 31.



### **TYPICAL CHARACTERISTICS (continued)**

# DIFFERENTIAL NONLINEARITY vs SAMPLES

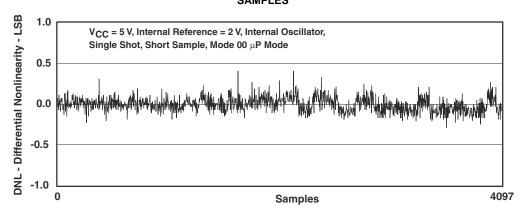


Figure 32.

#### MAGNITUDE vs FREQUENCY

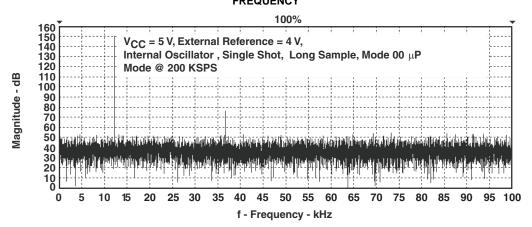
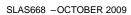


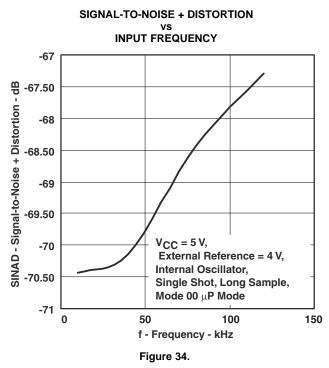
Figure 33.

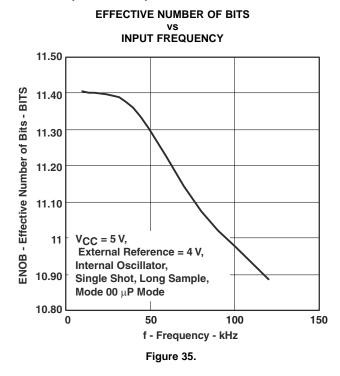




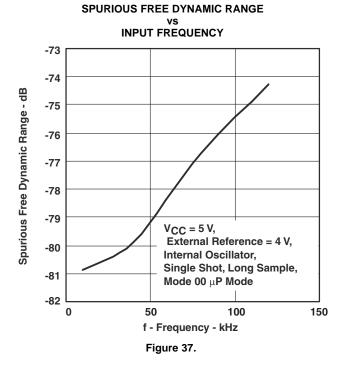
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#### TYPICAL CHARACTERISTICS (continued)





#### TOTAL HARMONIC DISTORTION vs INPUT FREQUENCY -69 -70 THD - Total Harmonic Distortion - dB -71 -72 -73 -74 -75 -76 $V_{CC} = 5 V$ External Reference = 4 V, -77 Internal Oscillator, Single Shot, Long Sample, -78 Mode 00 µP Mode -79 50 100 150 f - Frequency - kHz Figure 36.



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#### **TYPICAL CHARACTERISTICS (continued)**

## SIGNAL-TO-NOISE RATIO **INPUT FREQUENCY** -70.2 V<sub>CC</sub> = 5 V, External Reference = 4 V, Internal Oscillator, -70.4 SNR - Signal-to-Noise Ratio - dB Single Shot, Long Sample, Mode 00 µP Mode -70.6 -70.8 -71 -71.2 -71.4 100 150 f - Frequency - kHz

#### PRINCIPLES OF OPERATION

Figure 38.

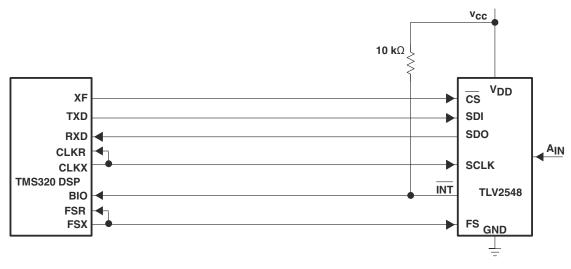


Figure 39. Typical Interface to a TMS320 DSP

#### DATA CODE INFORMATION

Parts with a date code earlier than 31xxxxx have the following discrepancies:

- 1. Earlier devices react to FS input irrespective of the state of the  $\overline{\text{CS}}$  signal.
- 2. The earlier silicon was designed with SDO prereleased half clock ahead. This means in the microcontroller mode (FS=1) the SDO is changed on the rising edge of SCLK with a delay; and for DSP serial port (when FS is active) the SDO is changed on the falling edge of SCLK with a delay. This helps the setup time for processor input data, but may reduce the hold time for processor input data. It is recommended that a 100-pF capacitance be added to the SDO line of the ADC when interfacing with a slower processor that



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requires longer input data hold time.

3. For earlier silicon, the delay time is specified as:

			MIN	NOM	MAX	UNIT
Delay time, delay from SCLK falling edge (FS is	V <sub>CC</sub> = 4.5 V	SDO = 0 pF	16			
Delay time, delay from SCLK falling edge (FS is active) or SDO = 100 pF 20 ns SCLK rising edge	V <sub>CC</sub> = 4.5 V	SDO = 100 pF	20			no
(FS = 1) to next SDO valid, $t_{d(SCLK-DOV)}$ .	V 07V	SDO = 0 pF	24			ns
3(352.1.201)	$V_{CC} = 2.7 \text{ V}$	SDO = 100 pF	30			

This is because the SDO is changed at the rising edge in the up mode with a delay. This is the hold time required by the external digital host processor, therefore, a minimum value is specified. The newer silicon has been revised with SDO changed at the falling edge in the up mode with a delay. Since at least 0.5 SCLK exists as the hold time for the external host processor, the specified maximum value helps with the calculation of the setup time requirement of the external digital host processor.

For an explanation of the DSP mode, reverse the rising/falling edges in item 2. above.



### PACKAGE OPTION ADDENDUM

31-May-2014

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	_	Pins	_	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
TLV2548MPWREP	ACTIVE	TSSOP	PW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	TV2548EP	Samples
V62/10603-01XE	ACTIVE	TSSOP	PW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	TV2548EP	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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### **PACKAGE OPTION ADDENDUM**

31-May-2014

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF TLV2548-EP:

Military: TLV2548M

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

## PACKAGE MATERIALS INFORMATION

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### TAPE AND REEL INFORMATION





A0	<u> </u>
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV2548MPWREP	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1

**PACKAGE MATERIALS INFORMATION** 

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TLV2548MPWREP	TSSOP	PW	20	2000	367.0	367.0	38.0	

PW (R-PDSO-G20)

### PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G20)

# PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
  C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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